


<b>Search Notes</b>  	<b>Application/Control No.</b>  10811403	<b>Applicant(s)/Patent Under Reexamination</b>  CHEN ET AL.
	<b>Examiner</b>  Tran, Mai T	<b>Art Unit</b>  2129

SEARCHED			
Class	Subclass	Date	Examiner
706	15, 19	6/18/2007	mtt
702	6	6/18/2007	mtt

SEARCH NOTES		
Search Notes	Date	Examiner
EAST	6/18/2007	mtt
Consulted with Kakali regarding 101 issue in claim 18	4/24/2007	mtt
ACM Portal	6/18/2007	mtt
Google	6/18/2007	mtt
IEEE	6/18/2007	mtt

INTERFERENCE SEARCH			
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US-PGPub, USPAT text search (Please see interference search history printout)		6/18/2007	mtt